

FORM PTO - 1449

INFORMATION DISCLOSURE STATEMENT

ATTORNEY DOCKET NO.: MIT-094CP2CN (5473/101)

APPLICANT(S): Shirley

SERIAL NO.: 10/721,148

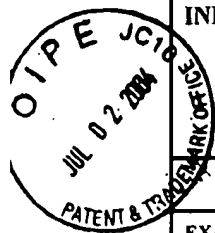
FILING DATE: November 25, 2003 GROUP: 2877

U.S. PATENT DOCUMENTS

EXAM. INIT.		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
35	A1	2001/0012388 A1	08/09/01	Muller et al.			03/04/98
	A2	3,994,589	11/30/76	Nodwell et al.			04/18/82
	A3	4,139,304	02-13-79	Redman, et al.	356	358	02-10-77
	A4	4,298,286	11-03-81	Maxey et al.	356	381	06-02-80
	A5	4,349,277	09-14-82	Mundy, et al.	356	376	06-11-80
	A6	4,499,492	02-12-85	Hutchin	358	107	02-07-83
	A7	4,781,455	11-01-88	Mächler, et al.	356	34	05-08-86
	A8	4,832,489	05-23-89	Wyant, et al.	356	359	03-19-86
	A9	5,146,293	09-08-92	Mercer, et al.	356	356	05-13-91
	A10	5,289,264	02-22-94	Steinbichler	356	376	09-25-92
	A11	5,455,670	10-03-95	Payne, et al.	356	5.1	05-27-93
	A12	5,621,529	04-15-97	Gordon et al.	356	376	04-05-95
	A13	5,666,197	08-09-97	Guerra	356	359	08-21-96
	A14	6,049,384	04-11-00	Rudd et al.	356	376	03-18-97
35	A15	6,438,272	08-20-02	Huang et al.	382	286	12-31-98

FOREIGN PATENT DOCUMENTS

EXAM. INIT.		DOCUMENT NUMBER	DATE	COUNTRY CODE	CLASS	SUB CLASS	FILING DATE	ABSTRACT ONLY	ENGLISH LANG (Y/N)
35	B1	2554086	06-16-77	DE			12-02-75	No	Abstract - Yes
	B2	2142427A	01-16-85	GB			05-21-84	No	Yes
	B3	61198009	09-02-86	JP			02-28-85	Yes	Yes
	B4	58173412	10-12-83	JP			04-05-82	Yes	Yes
	B5	97/29341	08-14-97	PCT			02-03-97	No	Yes
35	B6	28 50 092 A1	05/29/80	DE			11/18/78	No	No Abstract in English

EXAMINER: *[Signature]*DATE CONSIDERED *9/26/04*

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31	B7	44 04 663 A1	08/17/95	DE			02/14/94	No	No Abstract in English
	B8	0 864 847 A2	09/16/98	EP			03/05/98	No	No Abstract in English
	B9	0 864 847 A3	09/16/98	EP			03/05/98	No	No Abstract in English
32	B10	2 595 815	09/18/87	FR			03/17/86	No	No Abstract in English
OTHER ART, JOURNAL ARTICLES, ETC.									
EXAM. INIT.	OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication)								
33	C1	Butters, Von J. N., "Using the Laser to Measure Length," <i>Materialprüf</i> , 24:245-248 (July 7, 1982) (German Abstract).							
	C2	Zou <i>et al.</i> , "Two-Wavelength DSPI Surface Contouring Through the Temperature Modulation of a Laser Diode," <i>Optik</i> , 94(4):155-158 (1993).							
	C3	Peng <i>et al.</i> , "A Simplified Multi-Wavelength ESPI Contouring Technique Based on a Diode Laser System," <i>Optik</i> , 91(2):81-85 (1992).							
	C4	Fercher <i>et al.</i> , "Two-Wavelength Speckle Interferometric Technique for Rough Face Contour Measurement," <i>Optical Engineering</i> , 25(5):623-626 (May 1986).							
	C5	Fercher <i>et al.</i> , "Rough Surface Interferometry with a Two-Wavelength Heterodyne Speckle Interferometer," <i>Applied Optics</i> , 24(14):2181-1288 (July 15, 1985).							
	C6	Thalmann <i>et al.</i> , "Dimensional Profiling by Electronic Phase Measurement," <i>SPIE Industrial Laser Interferometry</i> , 746:61-68 (1987).							
	C7	Takeda <i>et al.</i> , "Fourier-Transform Speckle Profilometry: Three-Dimensional Shape Measurements of Diffuse Objects with Large Height Steps and/or Spatially Isolated Surfaces," <i>Applied Optics</i> , 33(34):7829-7837 (December 1, 1994).							
34	C8	Volotovskaya, N.K., "Relationship Between the Frequency and Angular Correlation Function of a Signal that is Scattered by an Extensive Body," <i>Radio Engineering and Electronic Physics J.</i> 16(6):1048-1049 (June 1971).							
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28	C9	Dresel <i>et al.</i> , "Three-Dimensional Sensing of Rough Surfaces by Coherence Radar," <i>Applied Optics</i> , 31(7):919-925 (March 1, 1992).	
	C10	Shirley <i>et al.</i> , "Advanced Techniques for Target Discrimination Using Laser Speckle," <i>Massachusetts Institute of Technology, The Lincoln Laboratory J.</i> , 5(3):367-440 (1992).	
	C11	Shirley, L. G., "Applications of Tunable Lasers to Laser Radar and 3D Imaging," <i>Technical Report 1025, Massachusetts Institute of Technology, Lincoln Laboratory</i> , (1995).	
	C12	K. Creath, "Phase-measurement interferometry techniques," <i>Chap. 5 in Progress in Optics XXVI</i> , E. Wolf Ed. pp. 349-393, Elsevier Science Publishers, New York, NY (1988).	
	C13	G.T. Reid, R.C. Rixon, and H.I. Messer, "Absolute and comparative measurements of three-dimensional shape by phase measuring moire topography," <i>Optics and Laser Technology</i> , 315-319, December, (1984).	
	C14	G. Indebetouw, "Profile measurement using projection of running fringes," <i>Applied Optics</i> , 17(18), 2930-2933 (1978).	
	C15	V. Srinivasan, H.C. Liu, and M. Halioua, "Automated phase-measuring profilometry of 3-D diffuse objects," <i>Applied Optics</i> , 23(18), 3105-3108 (1984).	
	C16	L.S. Wang, B.N. Dobbins, K. Jambunathan, and X.P. Wu, "Fibre optic shape measuring system using phase stepping speckle pattern interferometry," <i>SPIE</i> , 2088, M.J. Downs Ed., pp. 104-110 (1993).	
	C17	L.H. Bieman, "Absolute measurement using field shifted moire," <i>SPIE</i> , 1614, 259-264 (1991).	
	C18	H.O. Saldner and J.M. Huntley, "Temporal phase unwrapping: application to surface profiling of discontinuous objects," <i>Applied Optics</i> , 36(13), 2770-2775 (1997).	
	C19	K. Creath, "Phase-shifting speckle interferometry," <i>Applied Optics</i> , Vol. 24, No. 18, (1985).	
	C20	J.M. Huntley and H.O. Saldner, "Shape measurement by temporal phase unwrapping and spatial light modulator-based fringe projector," <i>SPIE</i> , Vol. 3100, 185-192, (1997).	
	C21	R.W. Wygant, S.P. Almeida, O.D.D. Soares, "Surface inspection via projection interferometry," <i>Applied Optics</i> , Vol. 27, No. 22, (1988).	
	C22	D. Paoletti and S. Spagnolo, "Fast Fourier Transformed Electronic Speckle Contouring for Diffuse Surfaces Profilometry," <i>Optics and Lasers in Engineering</i> , 20, 87-96, (1994).	
	C23	G. Sansoni, L. Biancardi, U. Minoni, F. Docchio, "A Novel, Adaptive System for 3-D Optical Profilometry Using a Liquid Crystal Light Projector," <i>IEEE Transactions on Instrumentation and Measurement</i> , Vol. 43, No. 4, (1994).	
	C24	M. Chang, C. Ho, C. Hu, "A Design for an Optical Coordinate Measuring Machine System," <i>Proc. Natl. Sci. Counc. ROC(A)</i> , Vol. 18, No. 5, 477-484, (1994).	
28	C25	C. Joenathan, B. Pfiger, H.J. Tiziani, "Contouring by electronic speckle pattern interferometry employing dual-beam illumination," <i>Applied Optics</i> , Vol. 29, No. 13, (1990).	
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